



FOR IMMEDIATE RELEASE

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AEHR TEST SYSTEMS RECEIVES FOX™-15 SYSTEM ORDER

Fremont, CA (July 11, 2012) - Aehr Test Systems (Nasdaq: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, announced today that it has received orders for a FOX-15 wafer-level burn-in system and a WaferPak cartridge aligner from a leading communication equipment manufacturer.

“We are very pleased that this customer has selected our FOX-15 wafer-level burn-in system for their production burn-in solution. We worked closely with them to design and supply a complete solution to meet their needs. The complete solution includes our patented WaferPak cartridge capable of burning-in over 10,000 die per wafer, an aligner used to align the wafer to the cartridge, the FOX-15 system capable of burning-in multiple wafers simultaneously and the program to stress the wafers. This complete solution, we believe, is very cost effective compared to package burn-in alternatives,” said Larry Anderson, vice president of worldwide sales of Aehr Test Systems.

Anderson added, “As this customer’s production needs increase, we expect they will require additional WaferPak cartridge capacity. These orders extend our FOX technology into the communications equipment industry and complement FOX systems already in use in the memory and automotive industries.”

The FOX-15 wafer-level burn-in system is a member of the FOX family of full wafer contact systems. The FOX-15 system provides cost effective test and high reliability burn-in of up to 15 wafers in parallel for applications such as automotive ICs, DRAMs, flash memory, sensors and VCSELs (laser diodes). The FOX-15 system performs burn-in of bare die at the wafer level so that Known Good Die (KGD) can be produced for stacked die and through silicon via (TSV) applications.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX family of test and burn-in systems and the DiePak® carrier. The ABTS system is used in production and

qualification testing of packaged parts for both low-power and high-power logic as well as all common types of memory devices. The FOX system is a full wafer contact test and burn-in system used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the FOX and WaferPak contactor technologies, acceptance by customers of the WaferPak contactors shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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